

# Algorithms for Generating Low-Distortion Single-Tone and Two-Tone Sinewaves Using an Arbitrary Waveform Generator

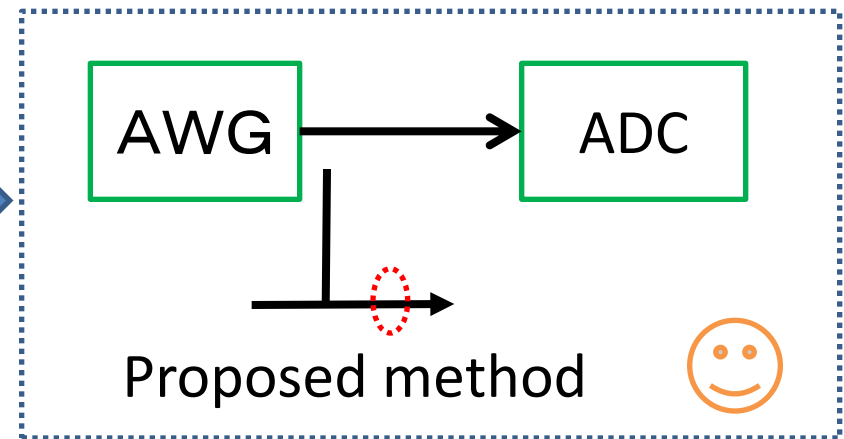
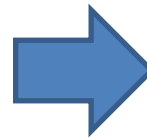
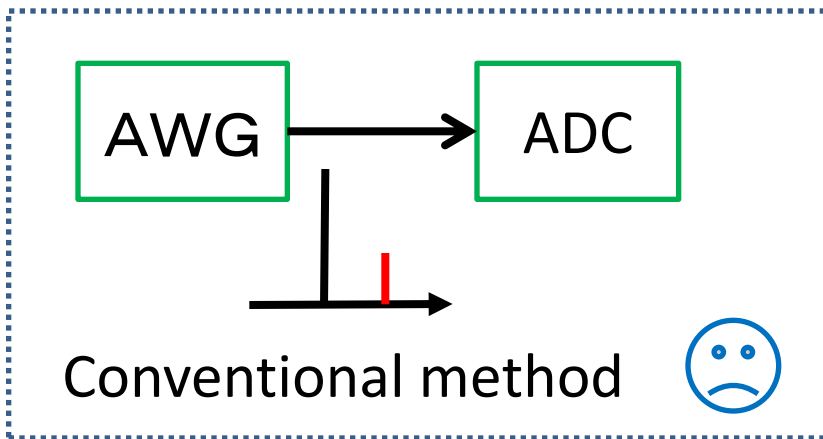
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Semiconductor Technology Academic Research Center

- Research Goal
- ADC Linearity Test
- Conventional Test Method
- Proposed Test Method
- Experimental Results
- Conclusions

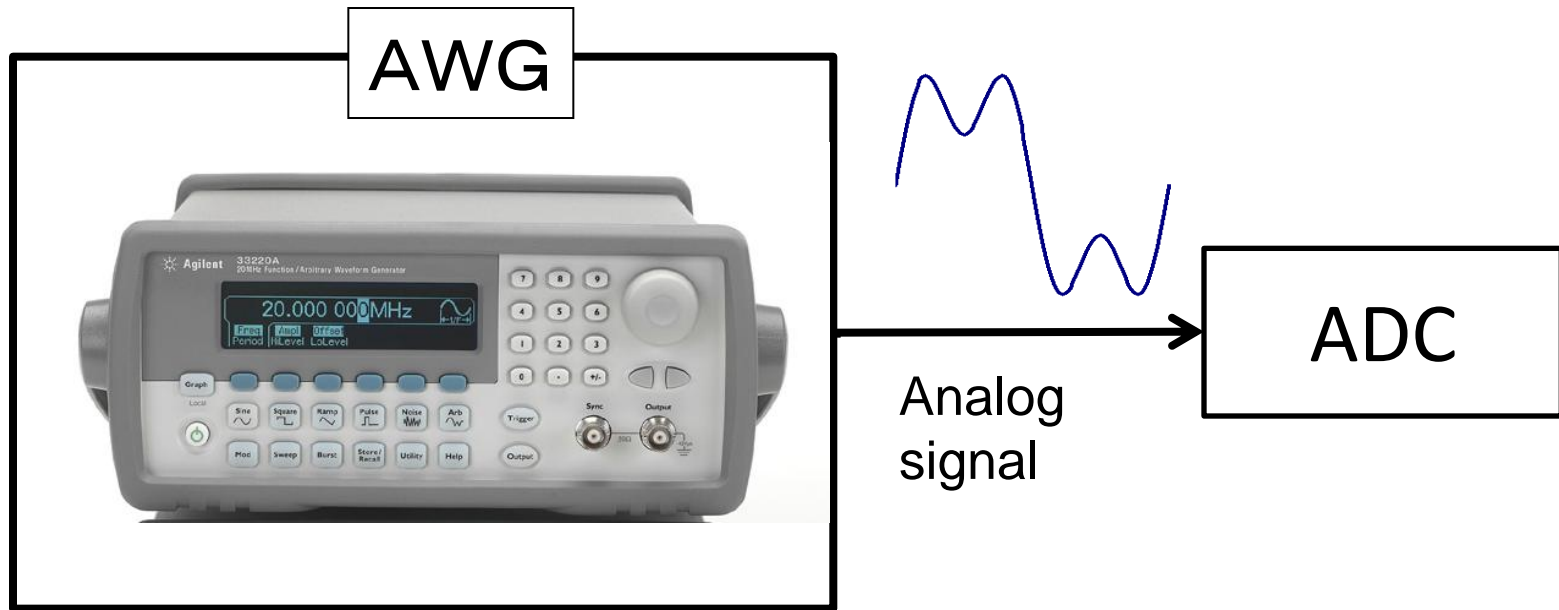
Generating low-distortion sinewaves  
for ADC linearity testing  
using low-cost AWG



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# Signal Generation with AWG

AWG ( Arbitrary Waveform Generator )



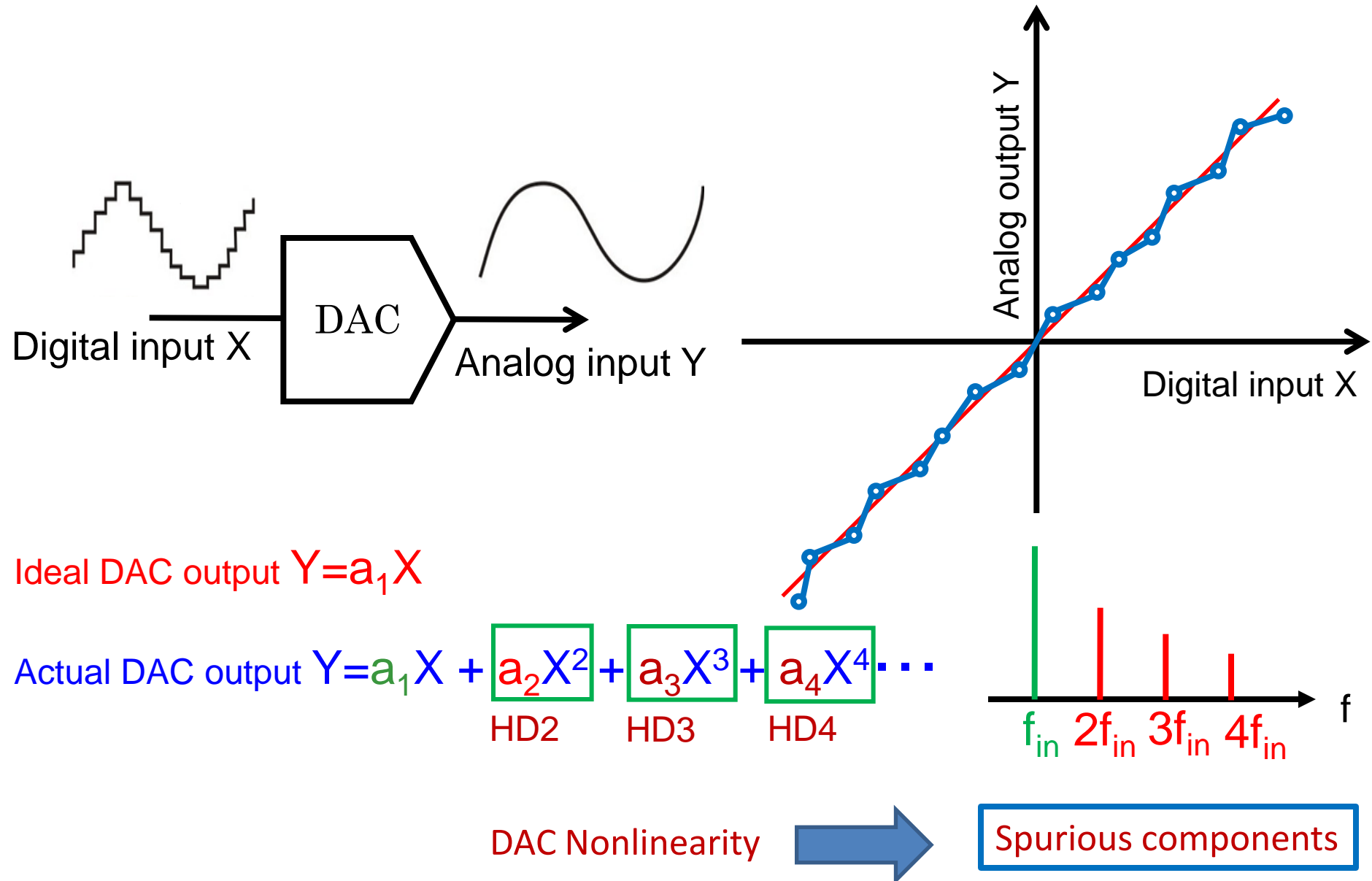
DSP generates digital signal. ➡ DAC converts it to analog signal.

Single-tone and two-tone analog signals for ADC testing

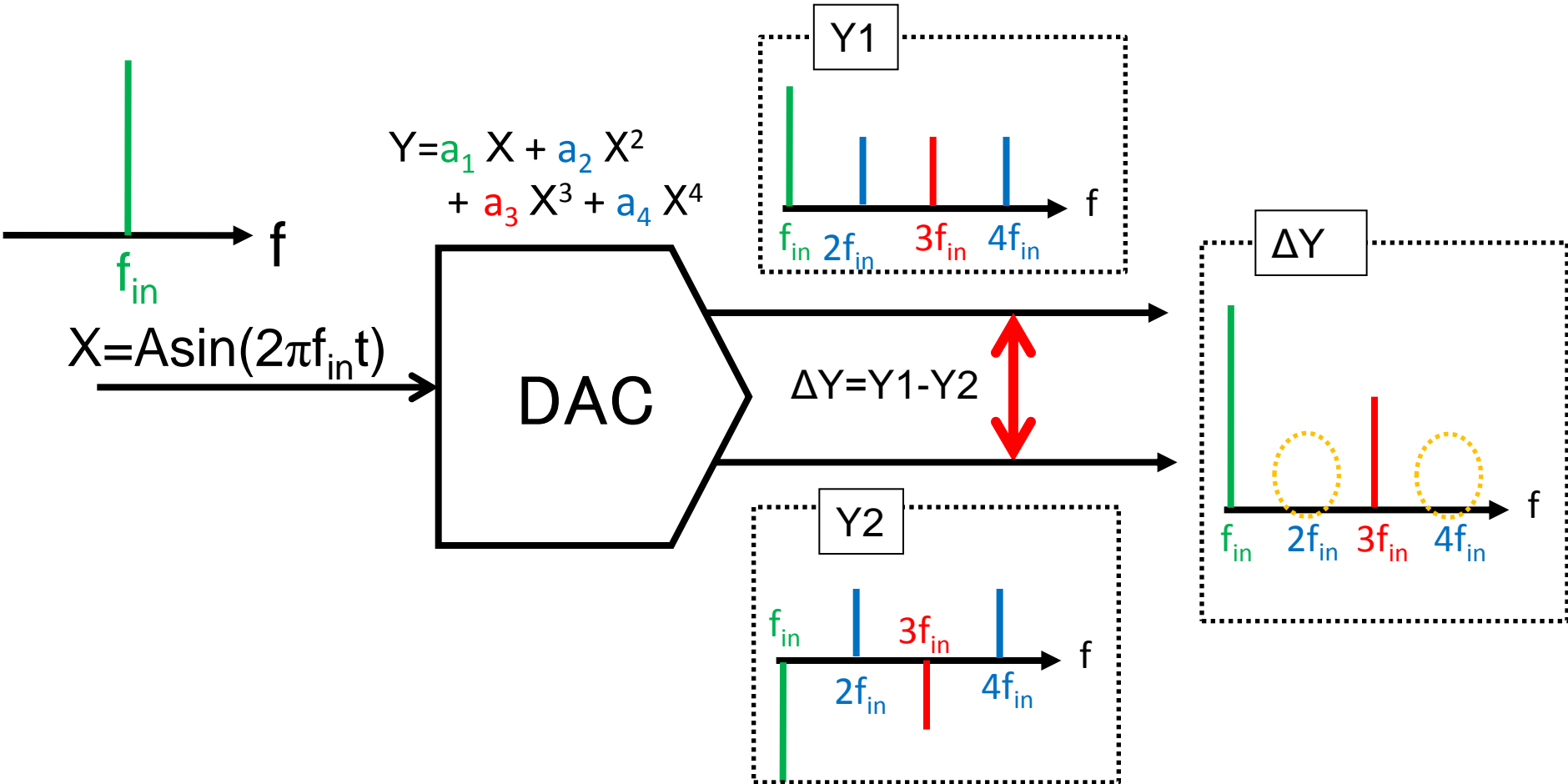


DAC has nonlinearity

# Spurious Components due to DAC Nonlinearity 6



# Use Differential Signals to Cancel Even Harmonics 7



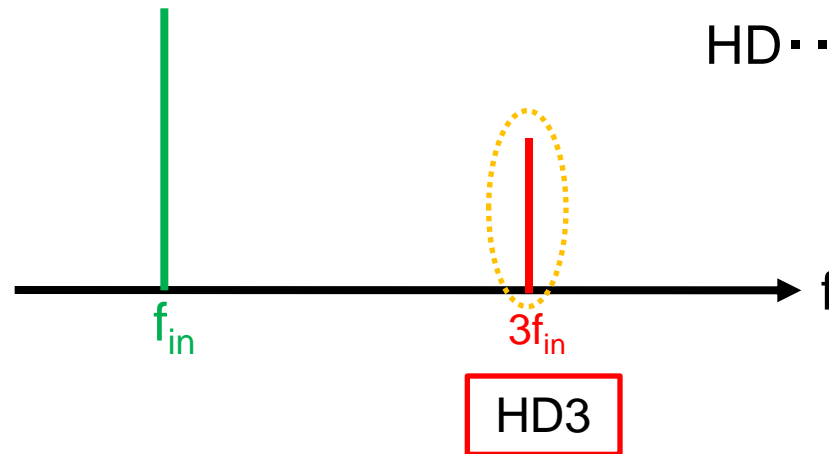
Use differential signals to cancel even harmonics.



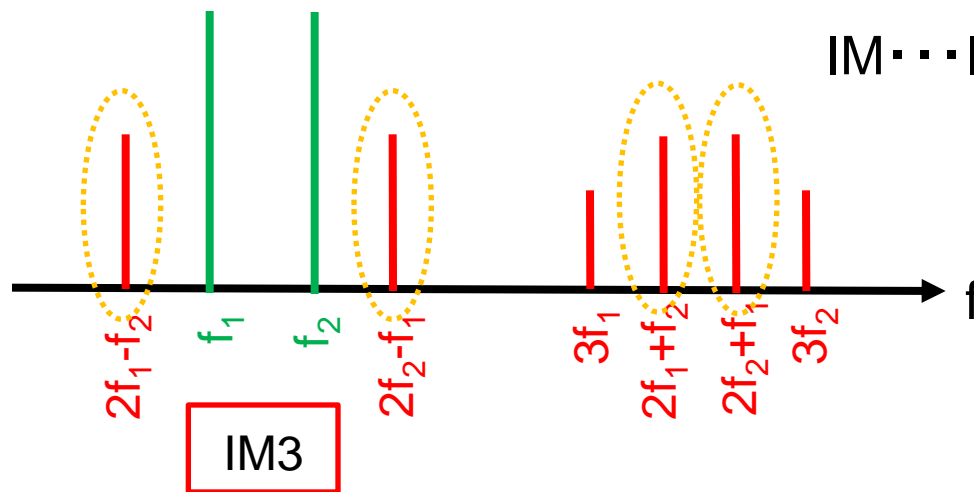
Next focus on removing third-order harmonics

# Third-order Nonlinearity Distortion Components 8

Single-tone input



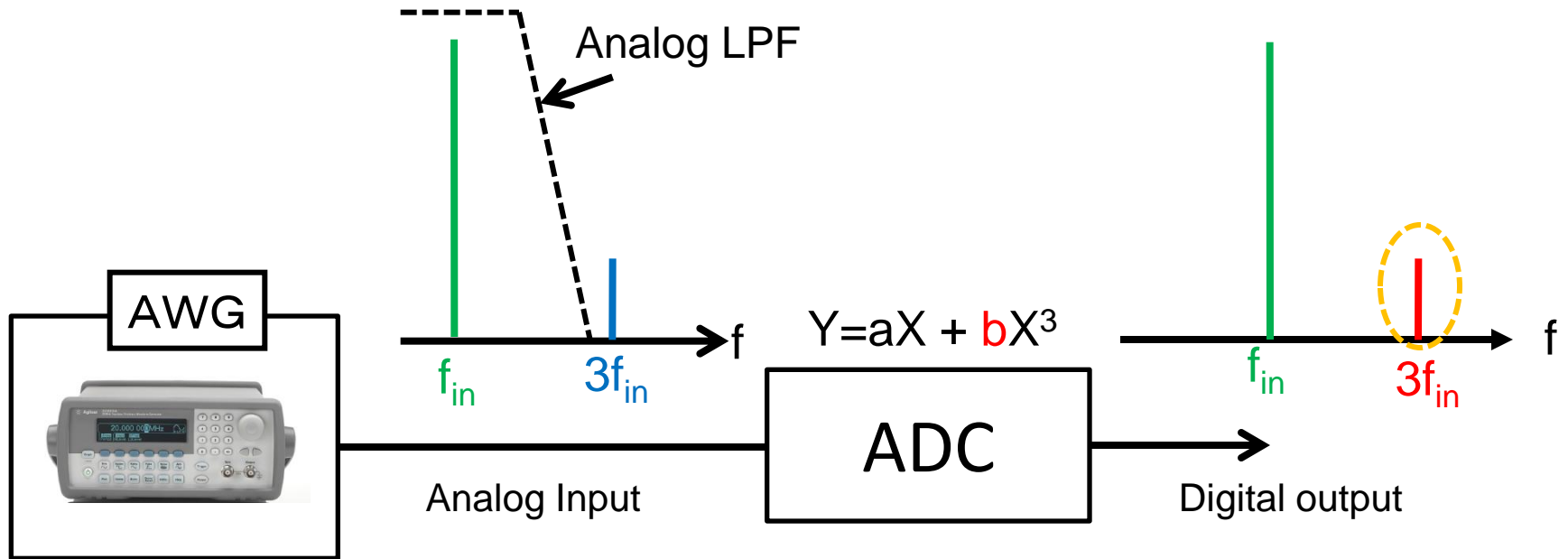
Two-tone input



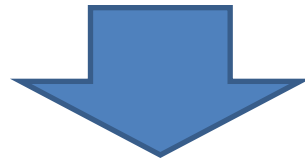
IM3 components are difficult to remove with analog filter



# ADC Linearity Test (Single-tone Input)

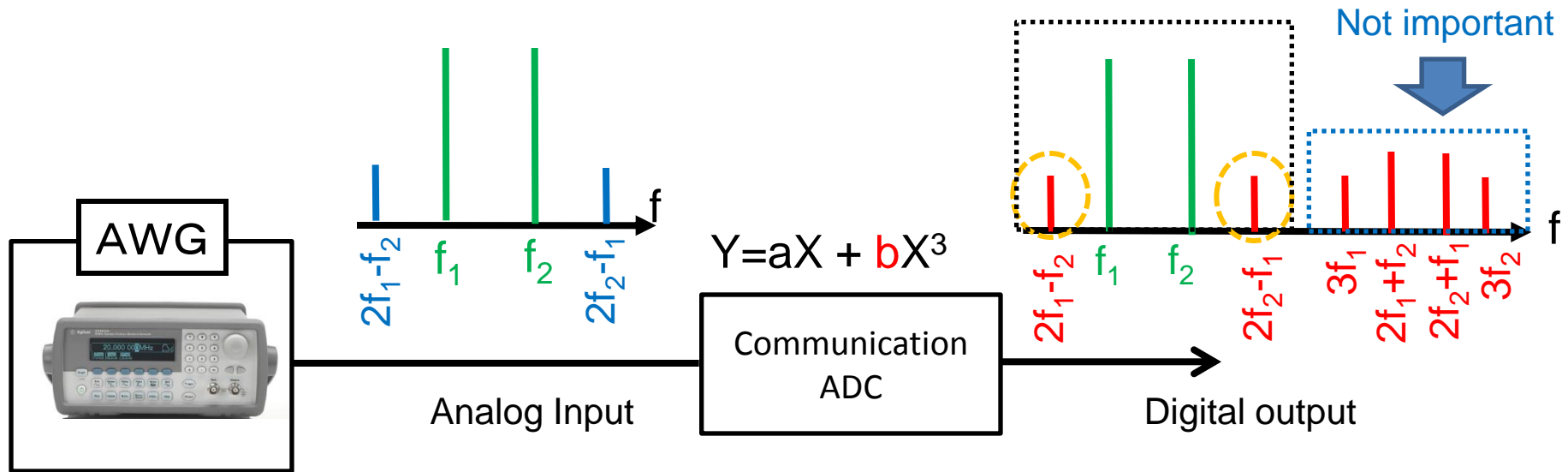


Can use analog LPF to remove HD3 (& higher harmonics)



ADC distortion can be measured & tested accurately.

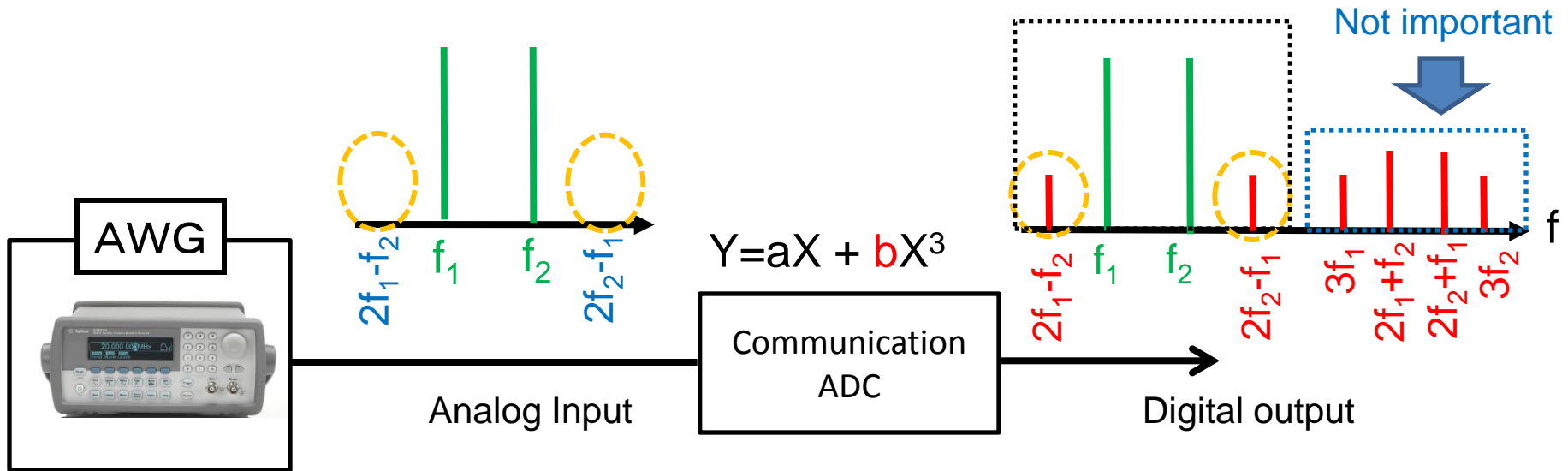
Communication  $\Rightarrow$  Narrow band, high frequency



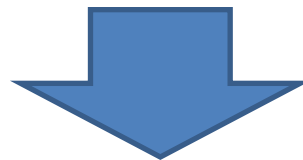
IM3 ( $2f_1 - f_2, 2f_2 - f_2$ ) components in input signal are

- within signal band
- difficult to remove by analog BPF.

Communication  $\Rightarrow$  Narrow band, high frequency

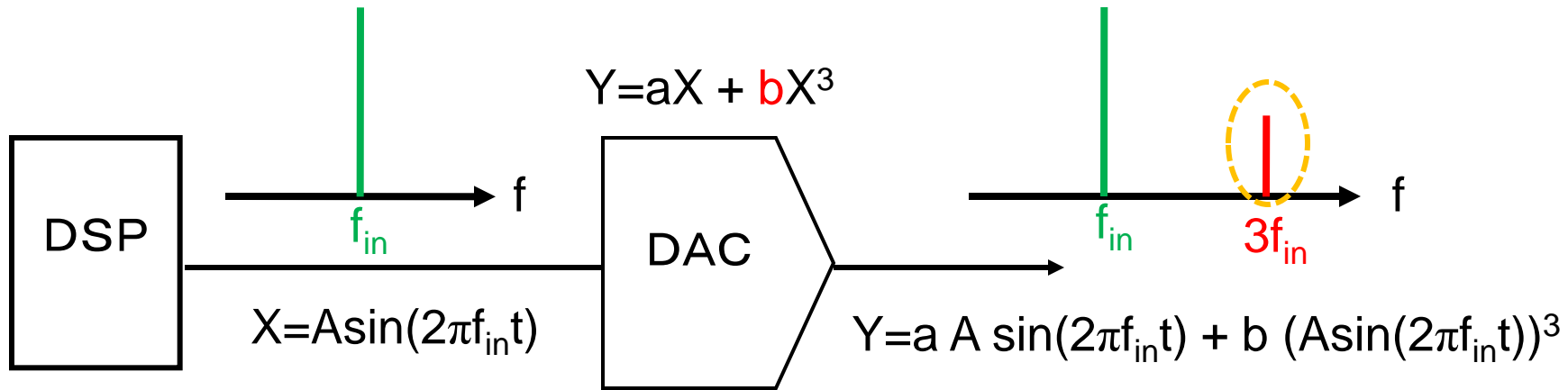


Use proposed method to cancel IM3 in analog input.



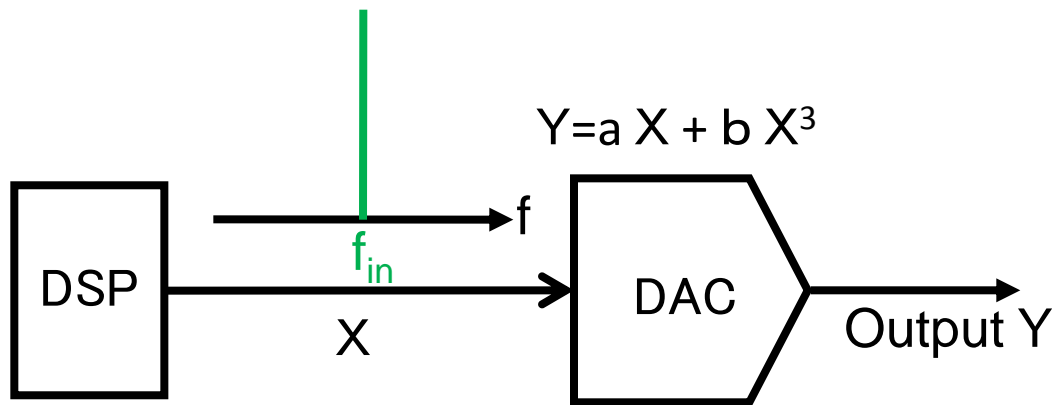
ADC distortion (IM3) can be measured & tested accurately.

- Research Goal
- ADC Linearity Test
- Conventional Test Method
- Proposed Test Method
- Experimental Results
- Conclusions



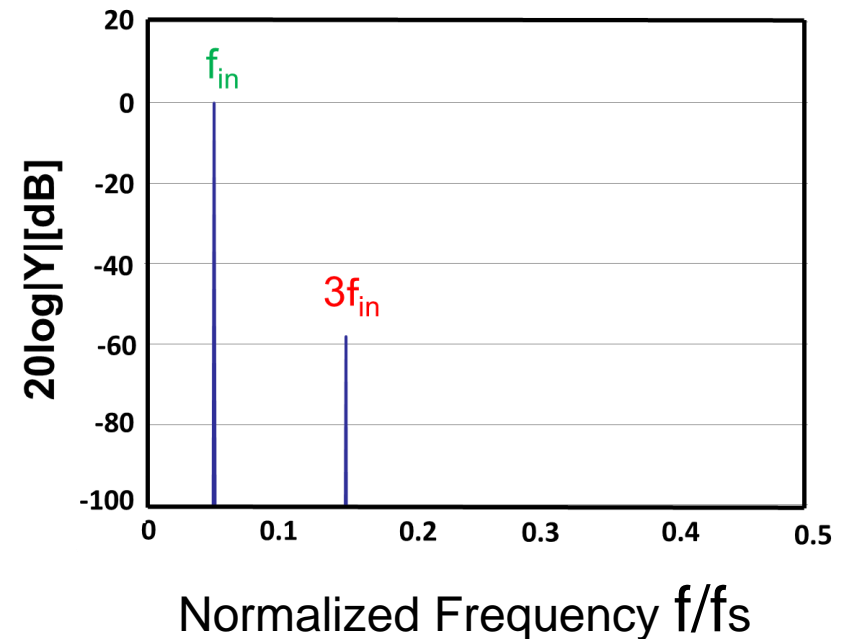
■ HD3 appears

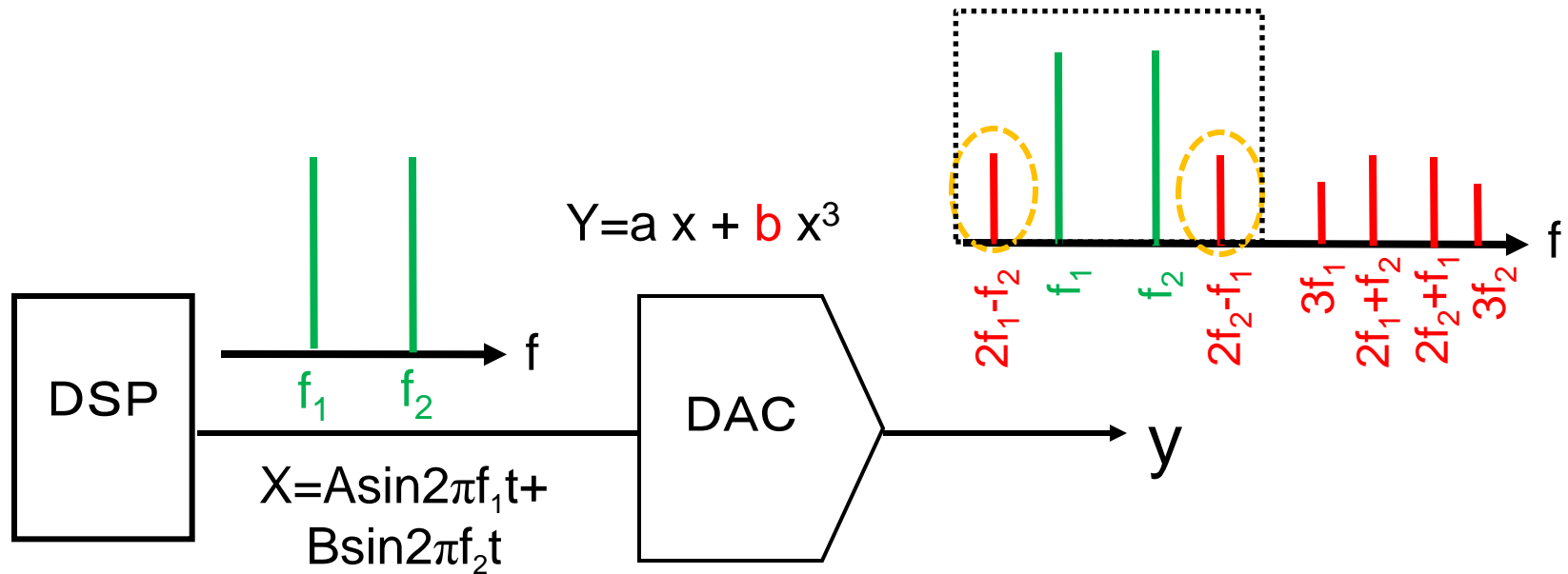
# Simulation Condition (Single-tone)



Output power spectrum is obtained by FFT

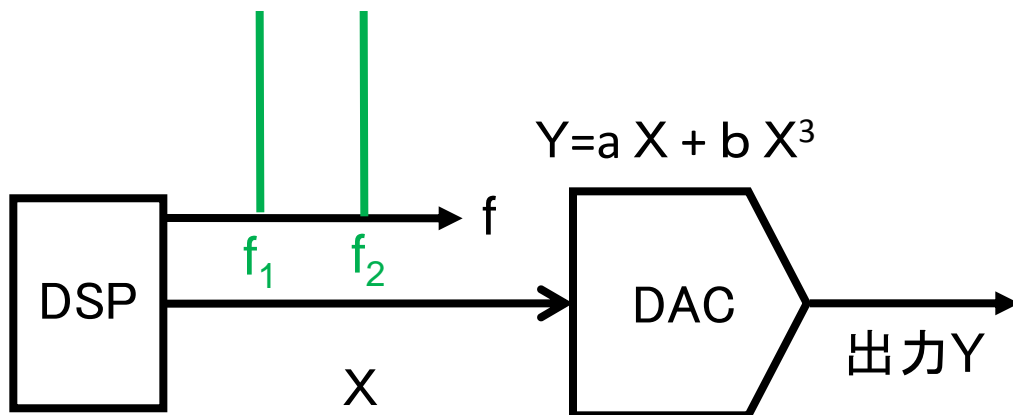
Input signal $X$	$\sin(2\pi f_{in} t)$
1 <sup>st</sup> coeff. $a$ (DAC)	1.0
3 <sup>rd</sup> coeff. $b$ (DAC)	-0.005
Input freq. $f_{in}$	51
Sampling freq. $f_s$	1024





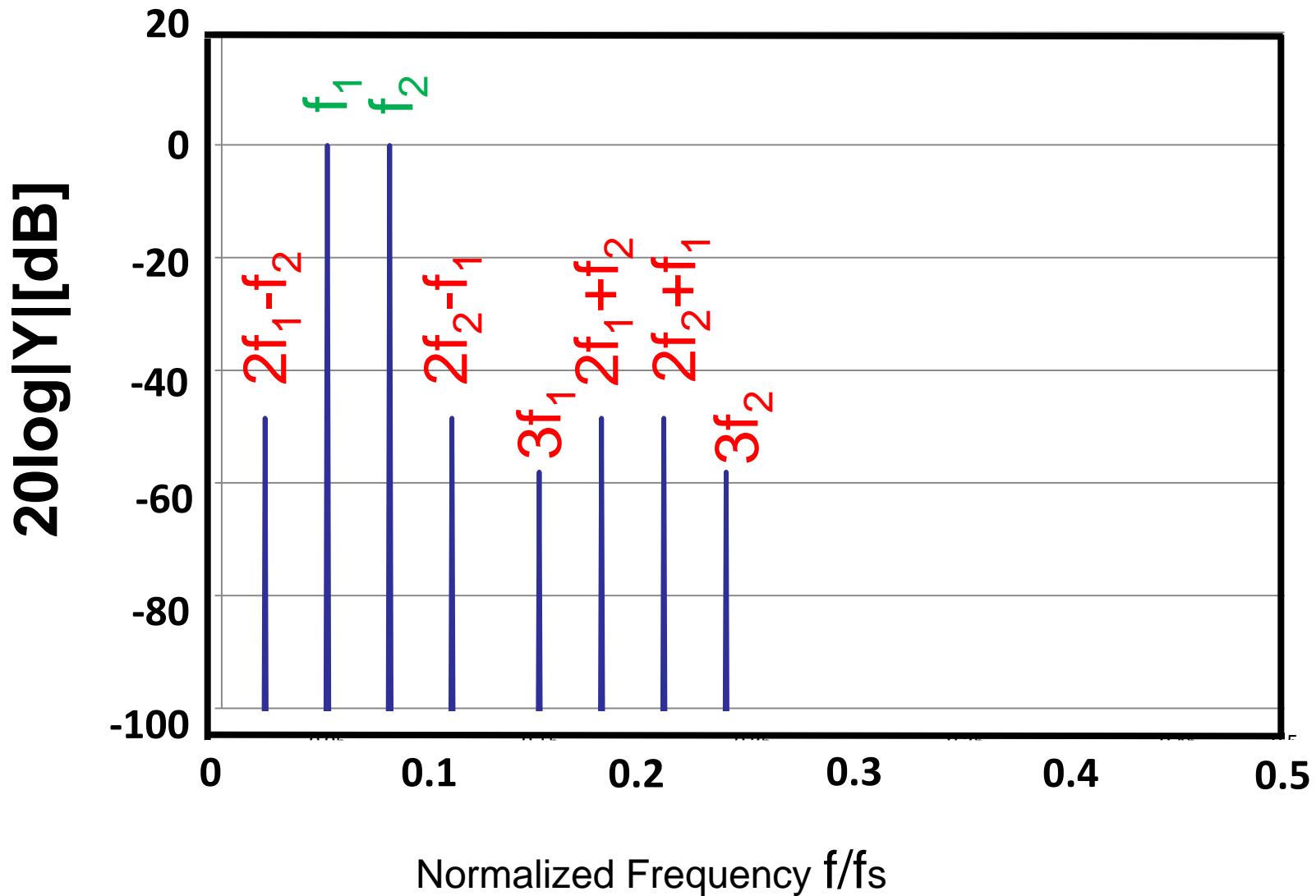
■ IM3 appears

# Simulation Condition (Two-tone)



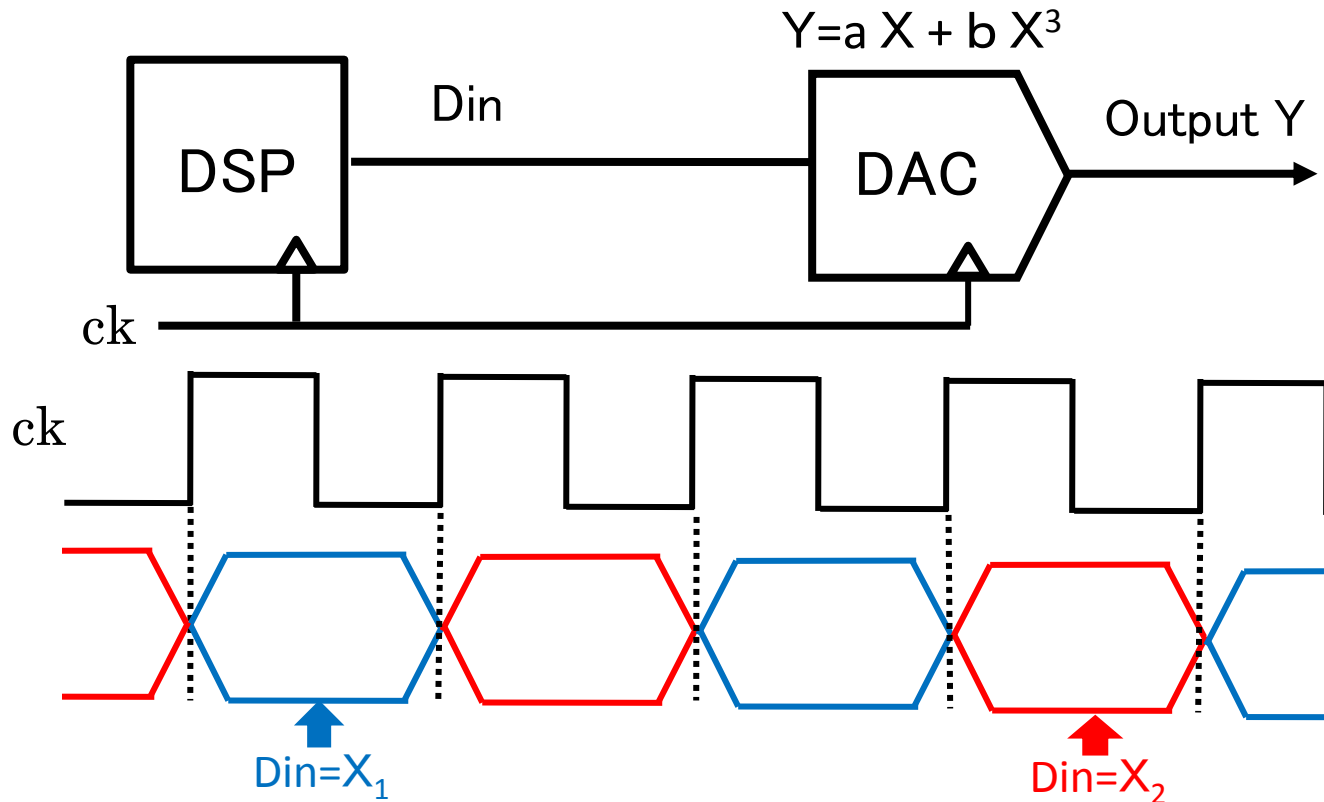
Input signal X	$\sin 2\pi f_1 t + \sin 2\pi f_2 t$
1 <sup>st</sup> coeff. a(DAC)	1
3 <sup>rd</sup> coeff. b(DAC)	-0.005
Input freq. f1	51
Input freq. f2	81
Sampling freq. fs	1024





- Proposed Test Method
  - Single-tone Generation
  - Two-tone Generation
  - Algorithm Generalization

# Proposed Method



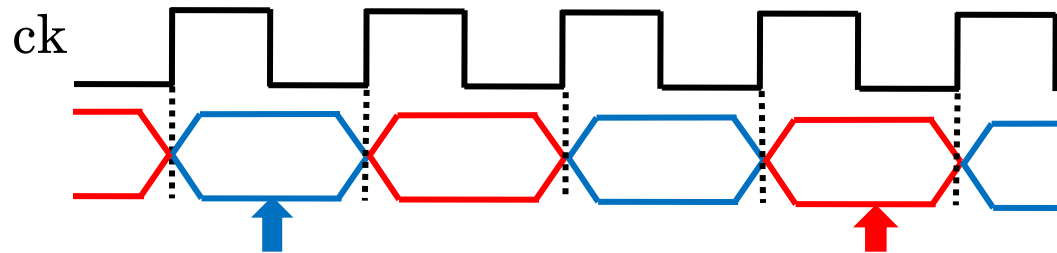
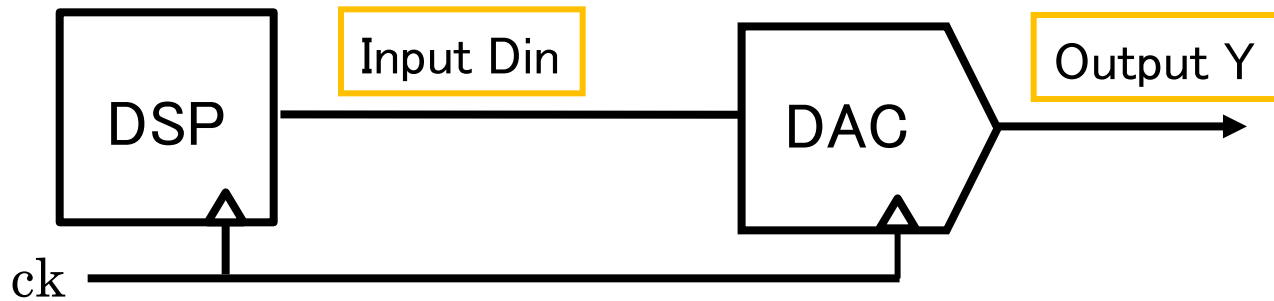
Interleave  $X_1$ ,  $X_2$  by one clock and generate  $D_{in}$

Feed  $D_{in}$  to DAC

Cancel distortion components of output  $Y$

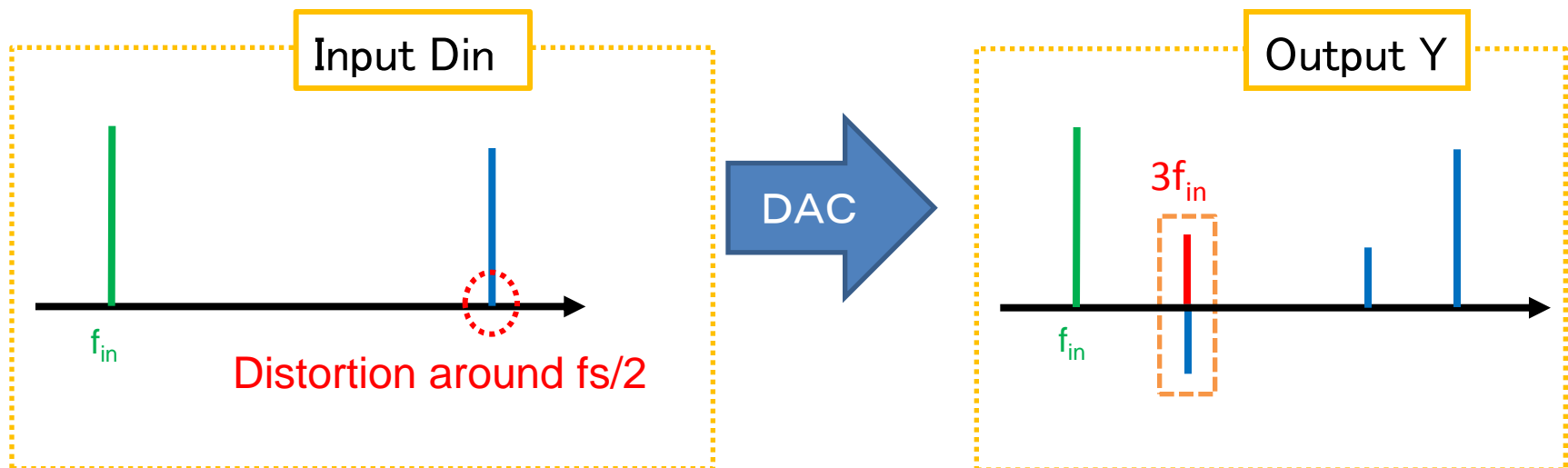
- ✓ Requires only DSP program change
- ✓ Spurious components are far from signal band

# Principle of Proposed Method

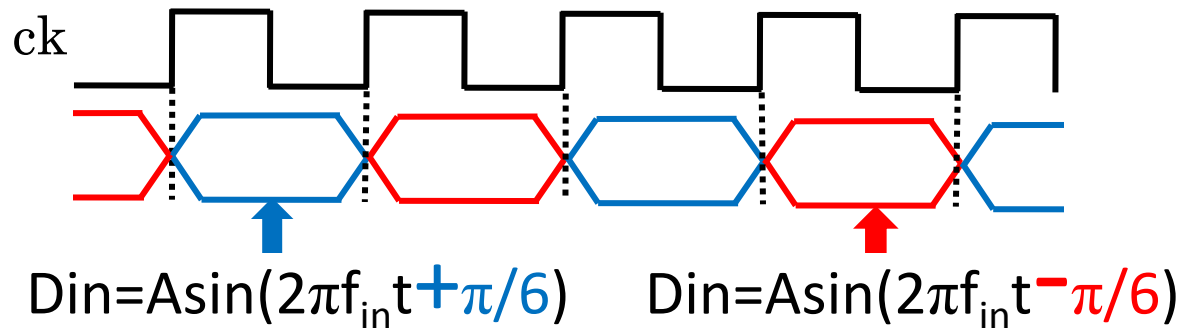
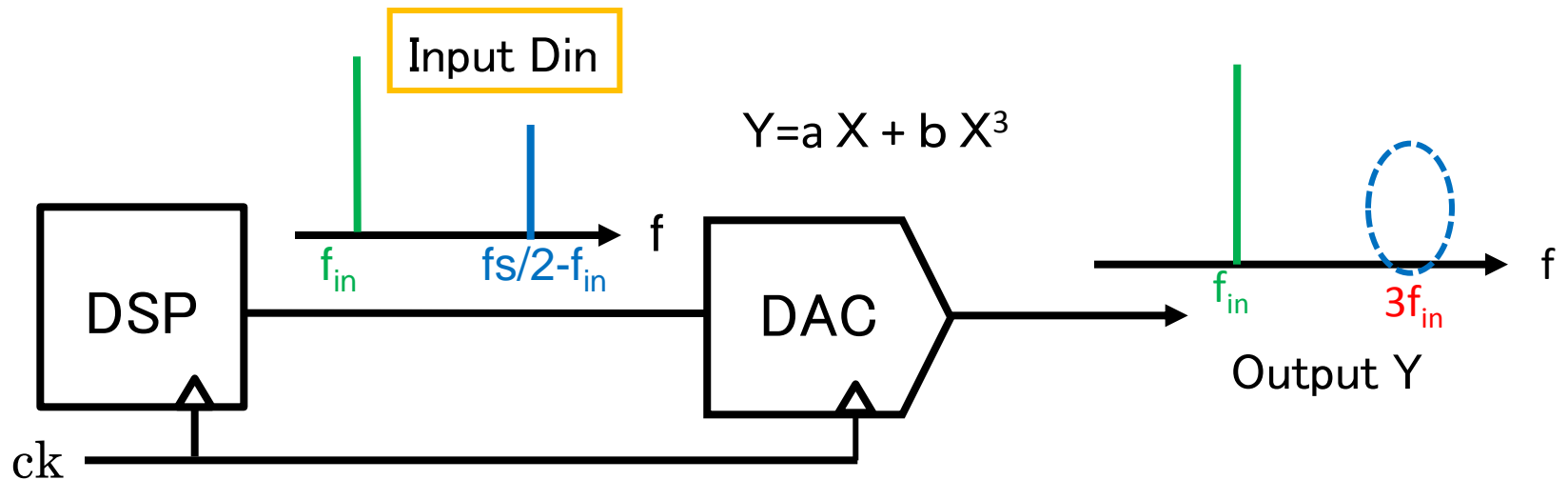


$$D_{in} = A \sin(2\pi f_{in} t + \pi/6)$$

$$D_{in} = A \sin(2\pi f_{in} t - \pi/6)$$



# Proposed Method (Single-tone)

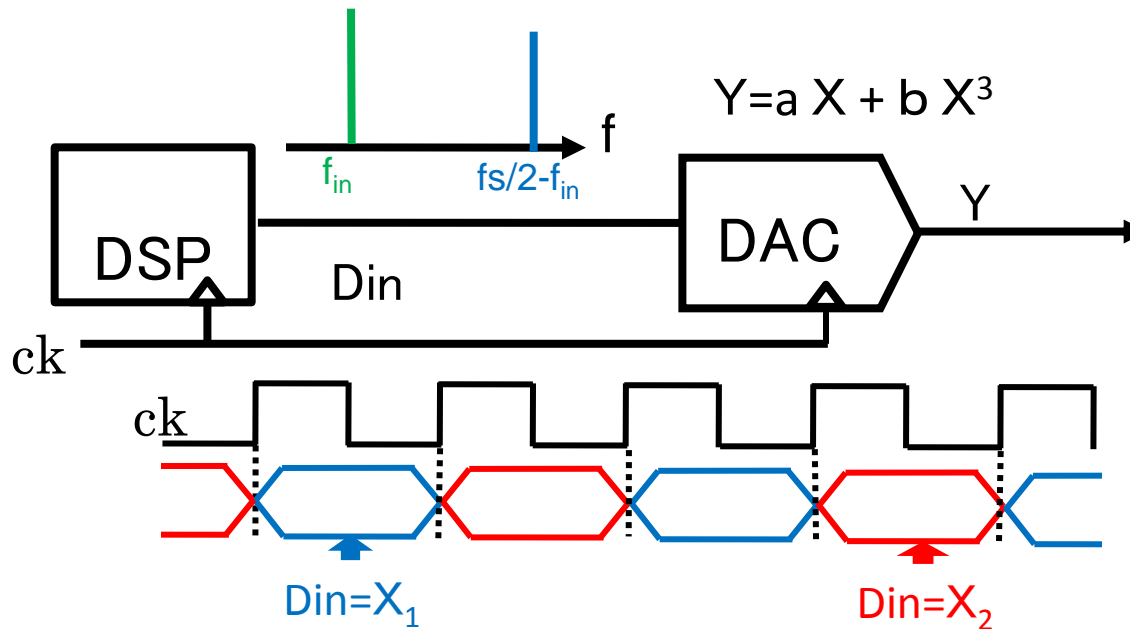


$$D_{in} = 0.87A \sin 2\pi f_{in} t + 0.5A \cos 2\pi(1/2f_s - f_{in})t$$

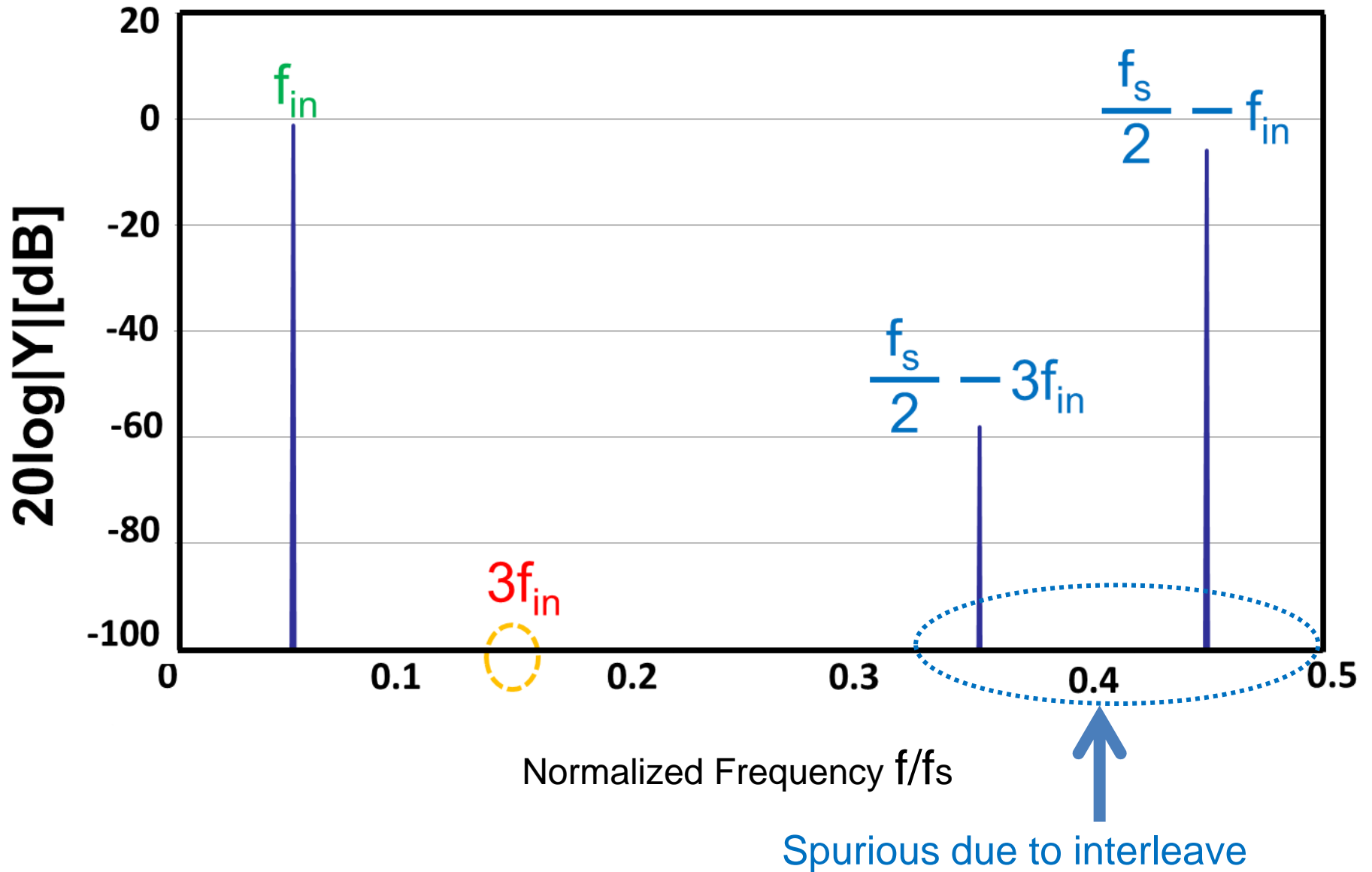
Fundamental  $f_{in}$  power reduction by 1.25dB

# Simulation Condition (Single tone)

22



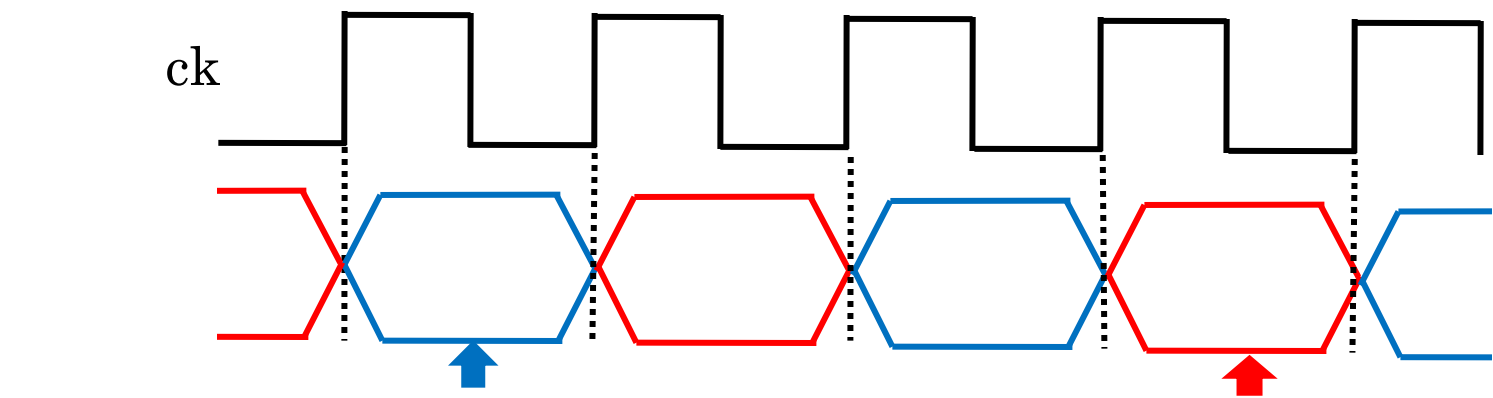
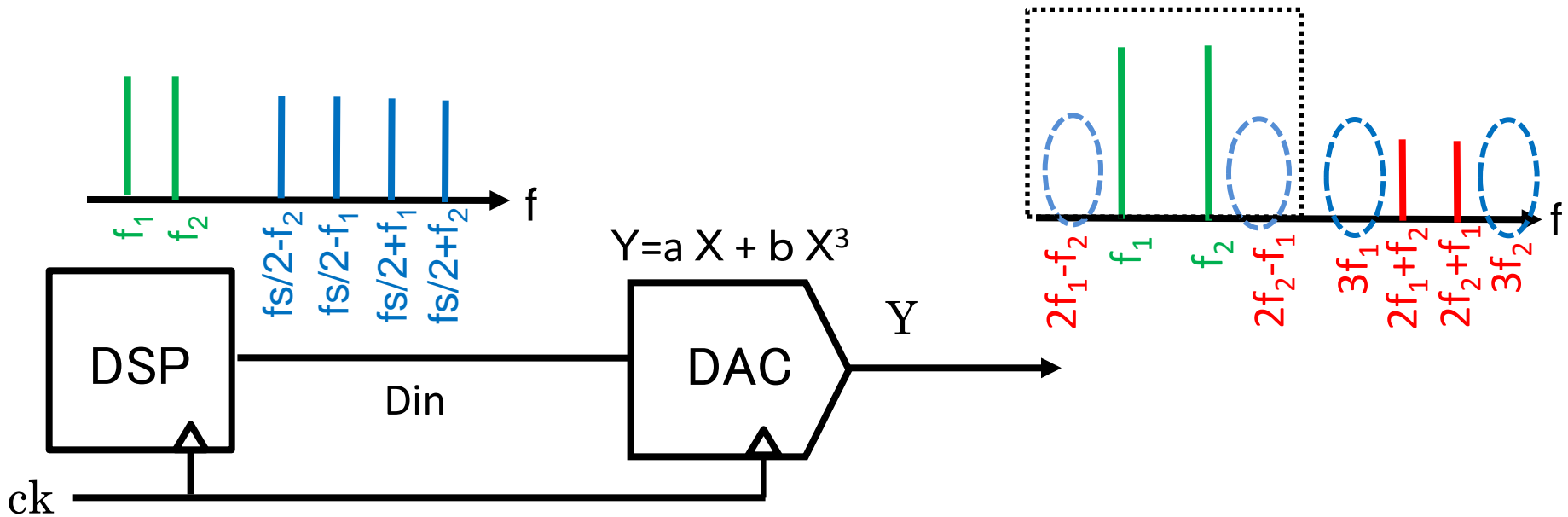
Input signal X1	$\sin(2\pi f_{in} t + \pi/6)$
Input signal X2	$\sin(2\pi f_{in} t - \pi/6)$
1 <sup>st</sup> coeff. a(DAC)	1
3 <sup>rd</sup> coeff. b(DAC)	-0.005
Input freq. $f_{in}$	51
Sampling freq. $f_s$	1024



- Proposed Test Method
  - Single-tone Generation
  - Two-tone Generation
  - Algorithm Generalization



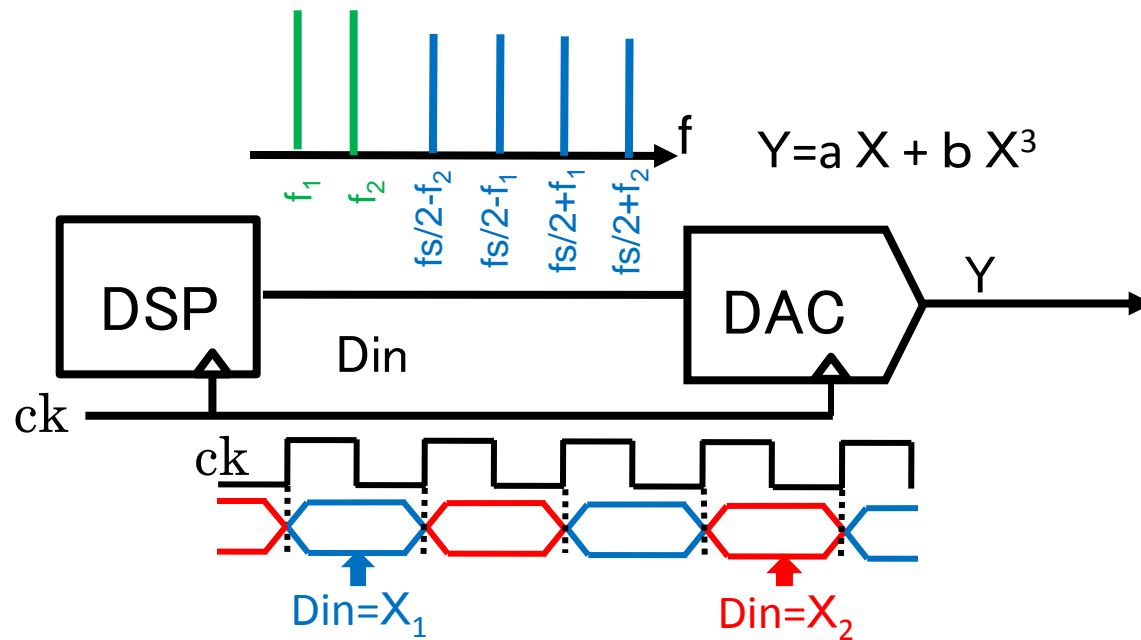
# Proposed Method (Two-tone signal)



$$D_{in} = A \sin(2\pi f_1 t + \pi/6) + B \sin(2\pi f_2 t - \pi/6)$$

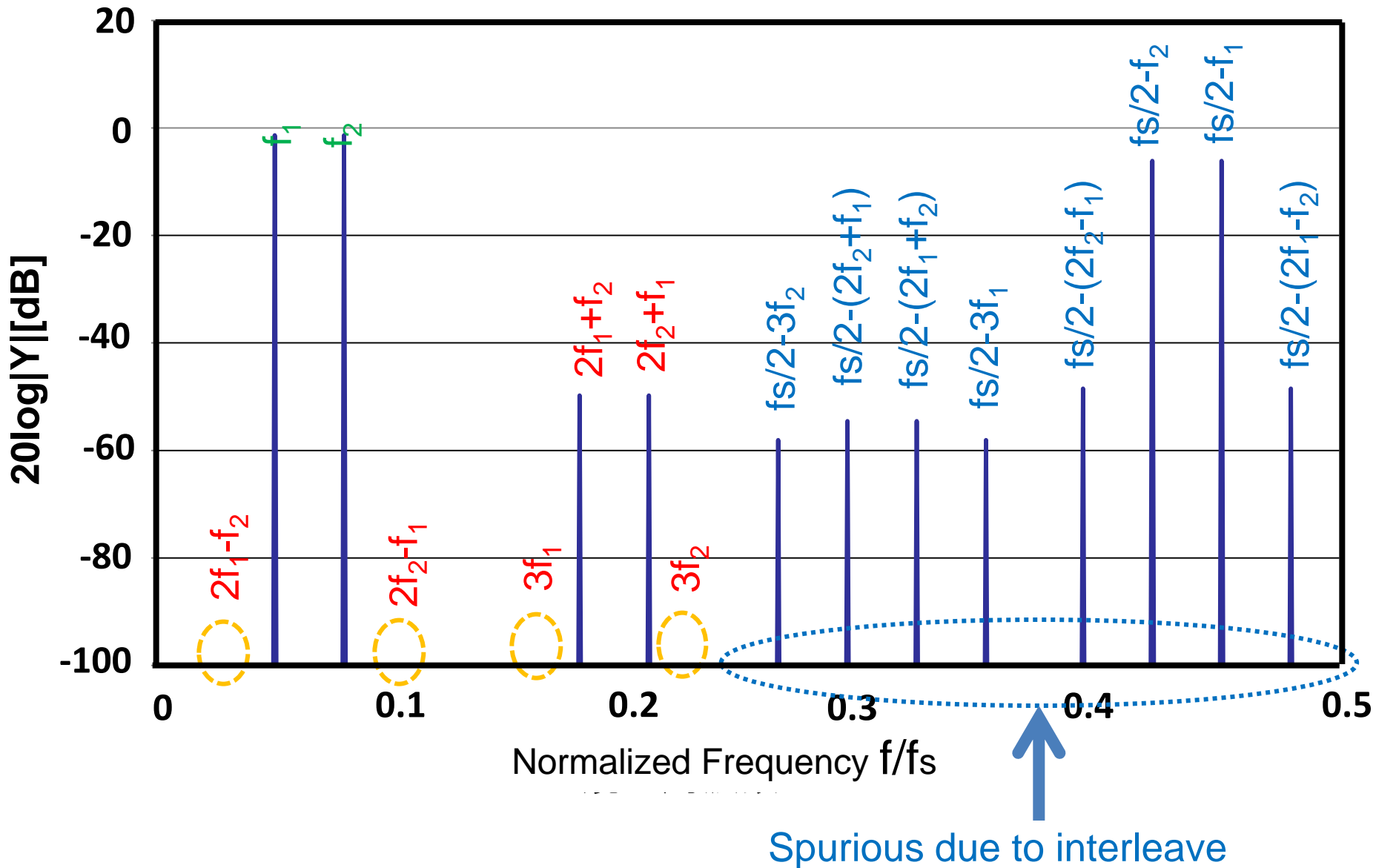
$$D_{in} = A \sin(2\pi f_1 t - \pi/6) + B \sin(2\pi f_2 t + \pi/6)$$

# Simulation Condition (Two tone)

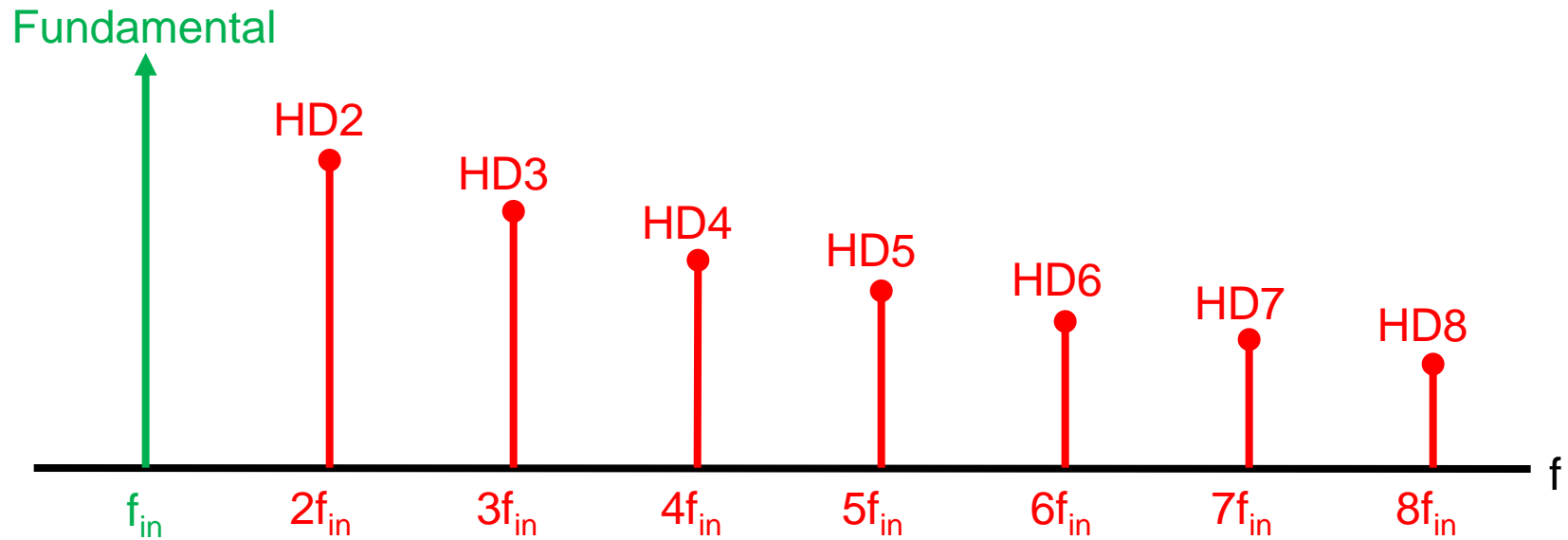


Input signal X1	$\sin(2\pi f_1 t + \pi/6) + \sin(2\pi f_2 t - \pi/6)$
Input signal X2	$\sin(2\pi f_1 t - \pi/6) + \sin(2\pi f_2 t + \pi/6)$
1 <sup>st</sup> coeff. a(DAC)	1
3 <sup>rd</sup> coeff. b(DAC)	-0.005
Input freq. f1	51
Input freq. f2	81
Sampling freq. fs	1024

# Output Power Spectrum (Two-tone Input) 27

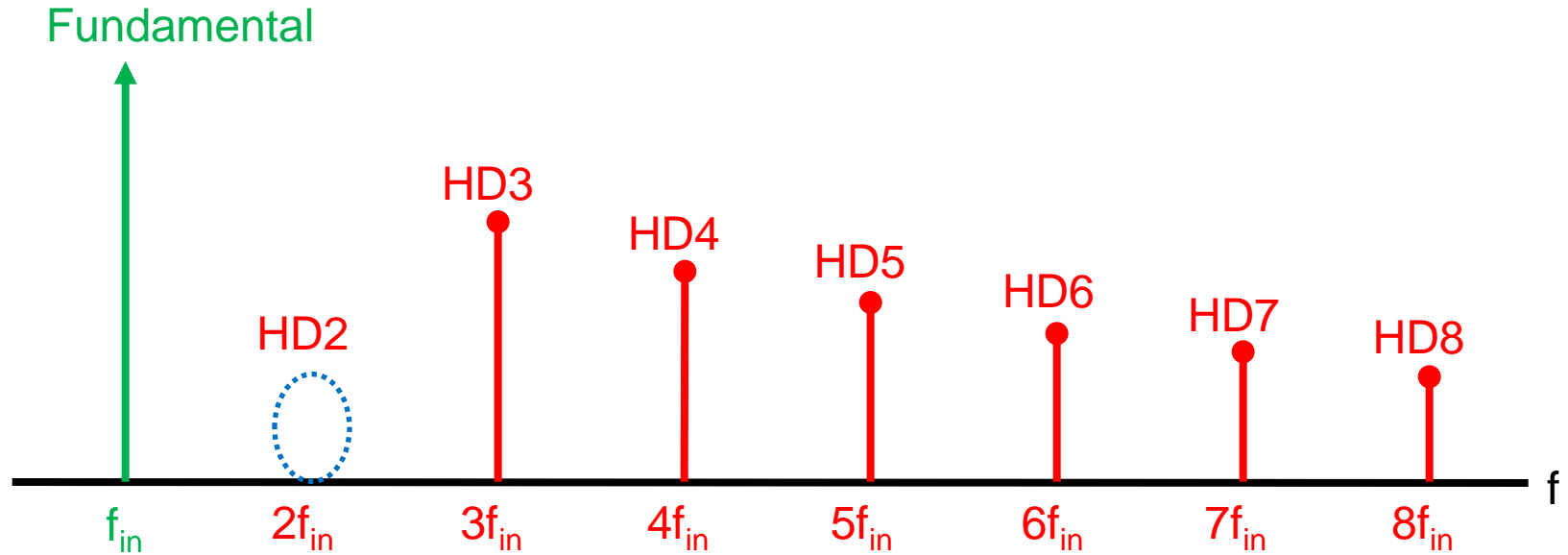


- Proposed Test Method
  - Single-tone Generation
  - Two-tone Generation
  - Algorithm Generalization



- ① HD2 cancellation
- ② HD2 & HD3 cancellation
- ③ HD3, HD5 & HD7 cancellation

# HD2 Cancellation

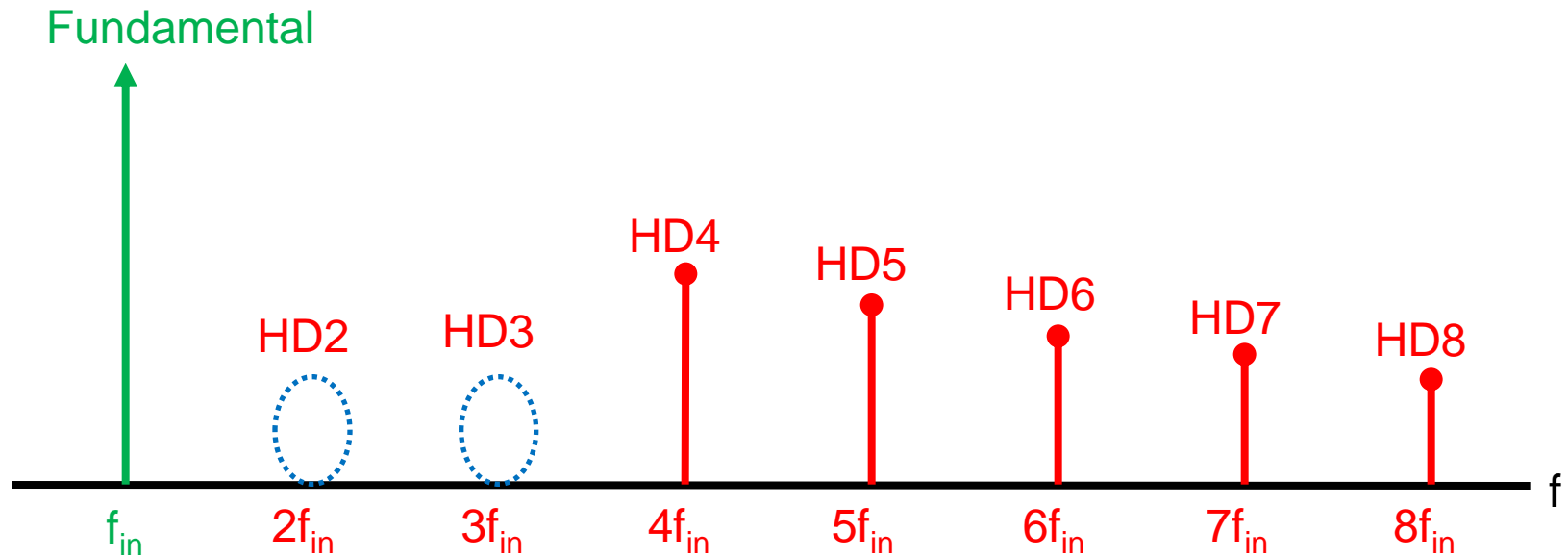


2-way interleave cancels  
HD2.

$$X_1 = A \sin(2\pi f_{in} t + \pi/4)$$

$$X_2 = A \sin(2\pi f_{in} t - \pi/4)$$

# HD2, HD3 Cancellation



4-way interleave cancels HD2 & HD3.

$$X_1 = A \sin(2\pi f_{in} t - \pi/4 - \pi/6)$$

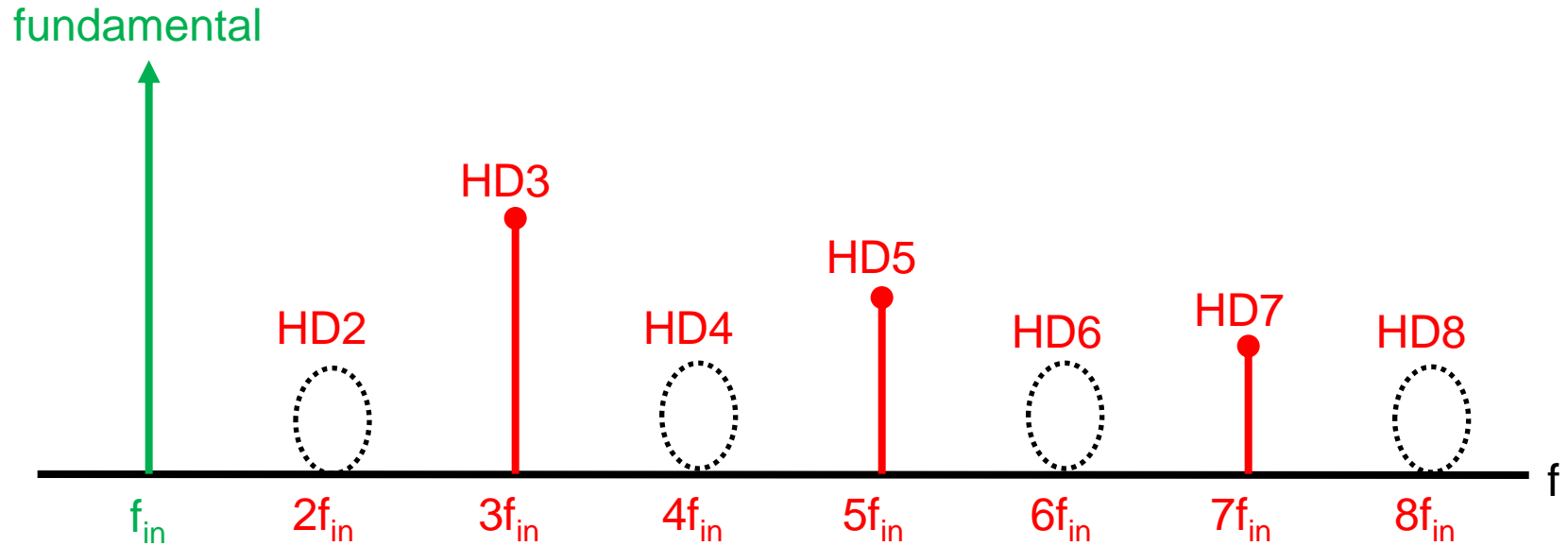
$$X_2 = A \sin(2\pi f_{in} t - \pi/4 + \pi/6)$$

$$X_3 = A \sin(2\pi f_{in} t + \pi/4 - \pi/6)$$

$$X_4 = A \sin(2\pi f_{in} t + \pi/4 + \pi/6)$$

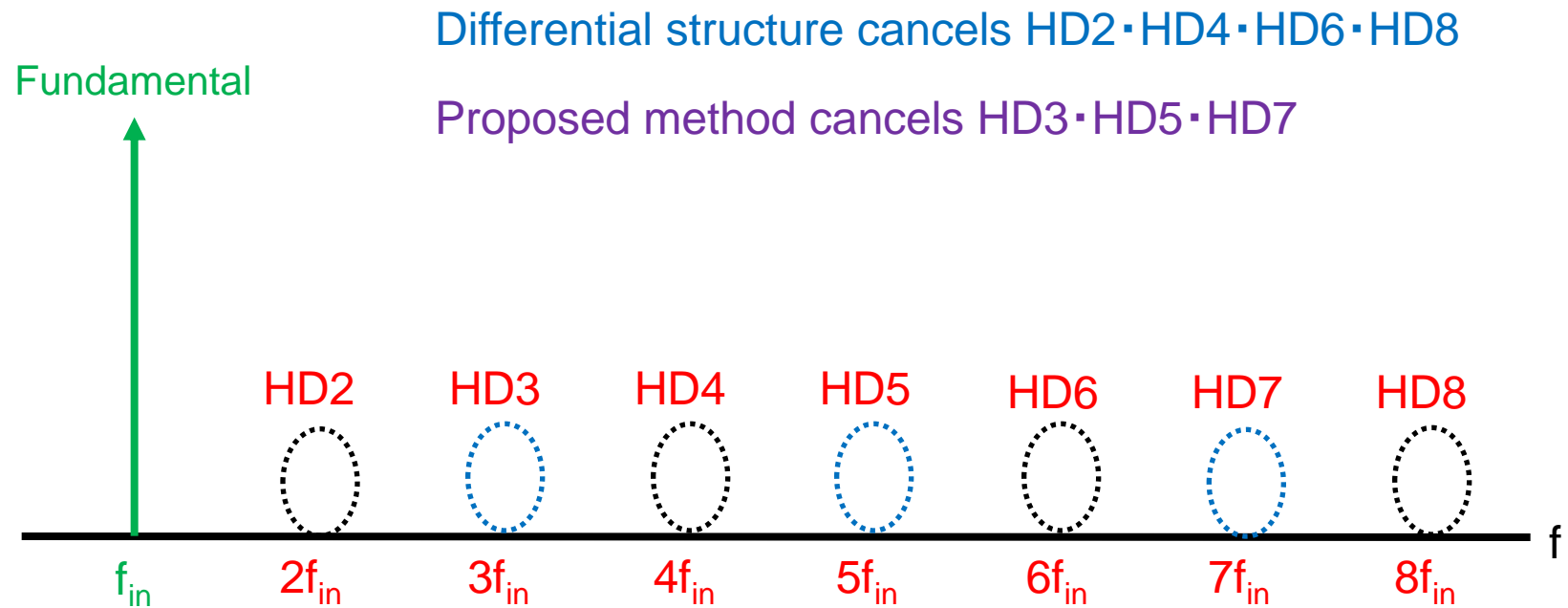
# Even Harmonic Cancellation

Differential structure cancels HD2 • HD4 • HD6 • HD8



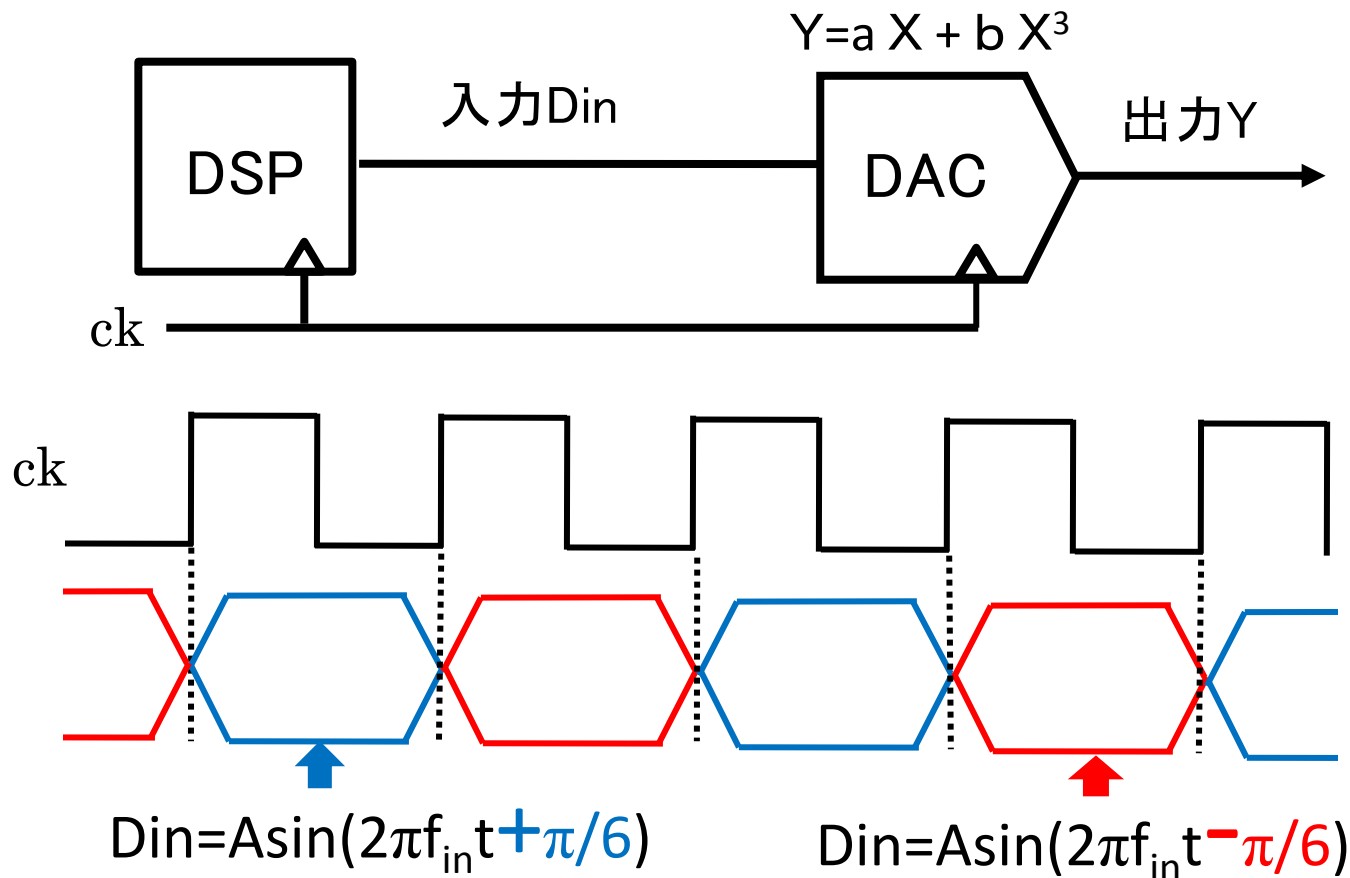


# HD3, HD5, HD7 cancellation



8-interleave cancels HD3, HD5 & HD7.

- Research Purpose
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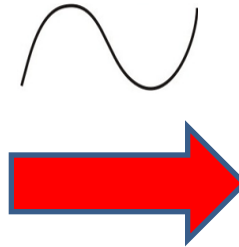
- Only DSP algorithm change in conventional AWG
- Single-tone generation with HD3 cancellation

# Experiment Instrumentation

AWG  
(Agilent 33120A)



Max. Sampling frequency (Hz)	40M
Resolution (bit)	12
Linearity	$\Delta$

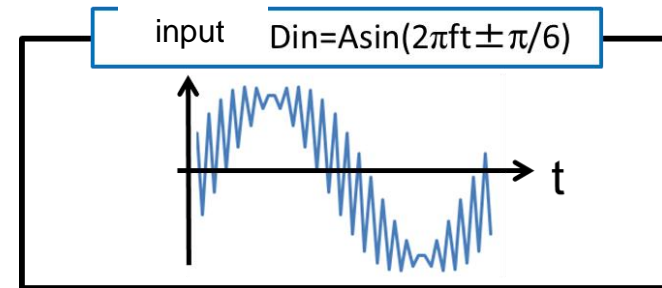
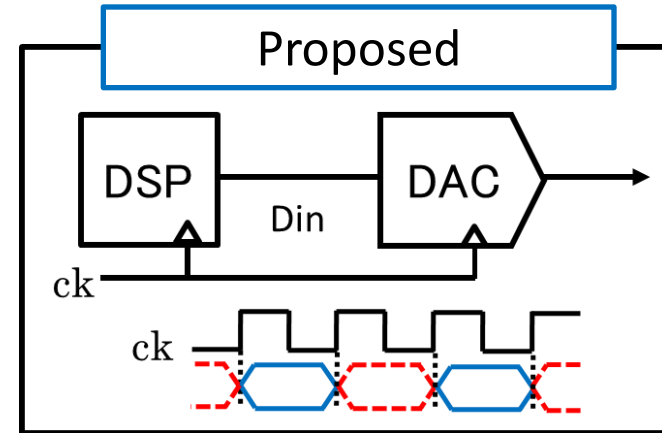
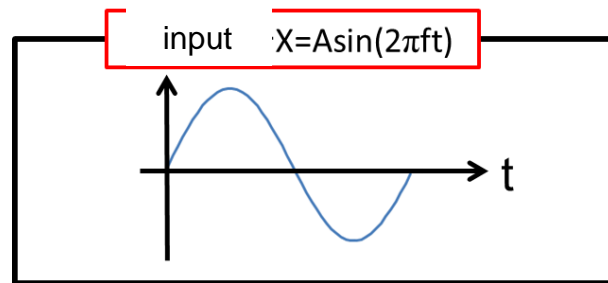
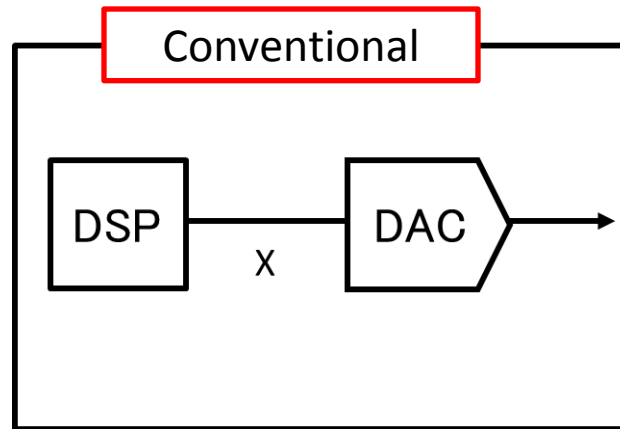


Spectrum Analyzer  
(HP ESA-L1500A)



Frequency range (Hz)	9k~1.5G
Max amplitude (Vpp)	19.8

# Experiment Condition



Conventional

Proposed



Fundamental  
(1MHz) : 6.31dBm

1.09dB

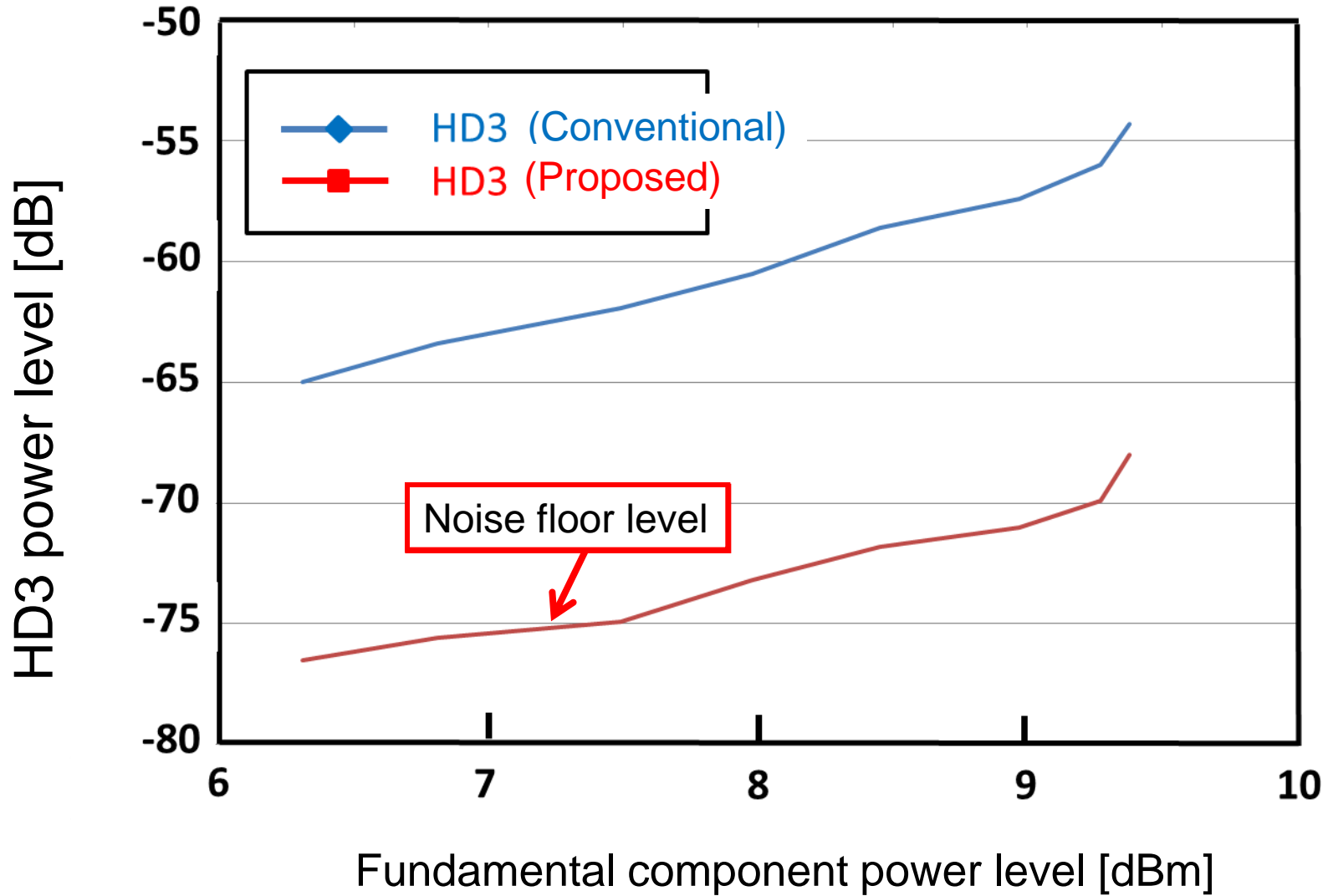
5.12dBm

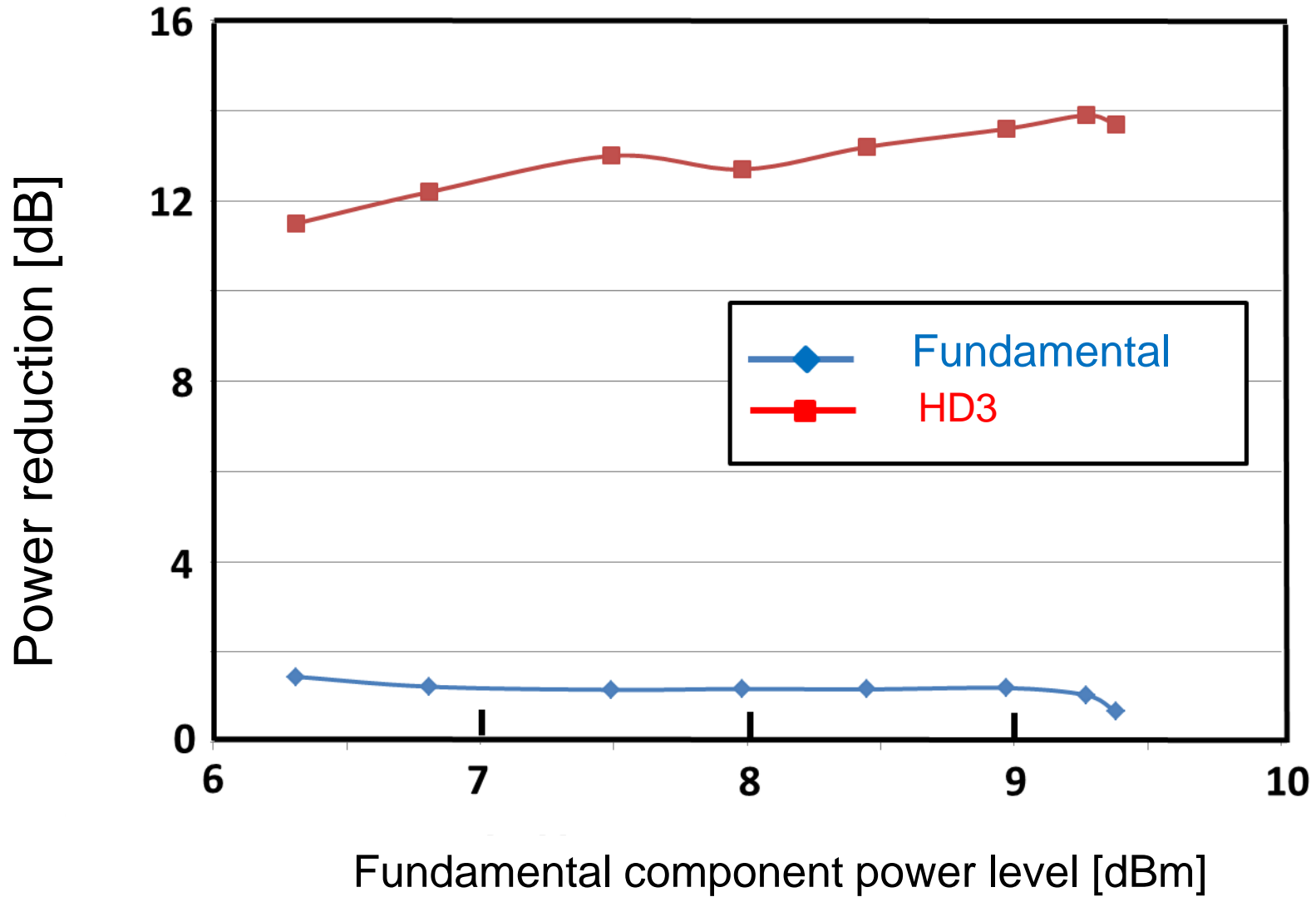
reduction

HD3(3MHz) : -65dBm

11.5dB

-76.5dBm  
(Noise floor level)







# Conclusions

- Low-distortion signal generation with AWG
- Single-tone: HD3 cancellation
- Two-tone: IM3 cancellation
- Algorithm generalization
- Only program change
- No hardware change.
- No need for AWG nonlinearity identification
- Theoretical analysis, simulation and experiment all verify the effectiveness of the proposed method



Low-cost, high-quality testing of ADC is possible